## Notice of References Cited Application/Control No. 10/629,917 Examiner VAN T. PHAM Applicant(s)/Patent Under Reexamination YONEZAWA, MINORU Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2002/0196717	12-2002	Masui et al.	369/44.29
*	В	US-5,475,662	12-1995	Miyagawa et al.	369/44.26
*	С	US-6,768,705	07-2004	Hirai, Yukio	369/44.28
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z	jp11-086309 Translation	03-1999	Japan	Ishibashi Junichi	
	0	jp08-077589 Translation	03-1996	Japan	Katayama Takeshi	
	Р					
	α					
	R					
	S					
	ı				·	

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	w	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.